



Deep Image Semantic Segmentation and Recognition

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Deadline for manuscript
submissions:

closed (31 December 2021)

Message from the Guest Editors

Dear Colleagues,

Recent advances in hardware development and deep neural network architectures on top of the availability of big image databases spurred many new research directions in the field of computer vision, detection, segmentation, semantics extraction and recognition. Motivation for these research efforts stems from various practical applications ranging from autonomous driving to robotics in agriculture, from medical image analysis and biometrics to geosensing, and many more application areas.

The aim of this special issue is to gather state of the art research to provide practitioners with broad overview of suitable deep neural network architectures and applications areas with objective performance metrics. We welcome well structured manuscripts with nicely illustrated background and novelty. We also recommend to authors to make the source code, databases, models and architectures publicly available, and to submit multimedia with each manuscript as it significantly increases the visibility and citations of publications.

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Guest Editors





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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